

System Features

AC Specification (Hardware)

	NandFlash
Test Frequency	Up to (Async: 200MHz, Sync: 83MHz (DDR 166MB/s), Toggle: 100MHz (DDR 200MB/s))
Switching Data Rate	20MB/s to 166MB/s 200MB/s (Toggle)
I/O Interface	ONFI 1.0, ONFI 2.0, ONFI 3.0, Toggle Nand Flash
Address Depth	Device size: 65536 blocks Block size: 8192 pages Page size: 32768 columns
Data Depth	x8, x16 per DUT site
Control Signal	Control Lines (Async): 4 CS#, 4 RYBY; 1 RE#, 1 ALE, 1 WP#, 1 CLE, 1 WE# in dual channel Control Lines (Sync): 4 CS#, 4 RYBY; 1 W/R#, 1 ALE, 1 WP#, 1 CLE, 1 CLK, 1 DQS in dual channel Control Lines (Toggle): 4CS#, 4RYBY, 1CLE, 1ALE, 1RE, 1WR, 1WP#, 1DQS in dual channel

	NandFlash
Programmable Timing	<p>Async Programmable Timing: tCLS, tCLH, tALS, tALH, tWP, tWH, tDS, tDH, tDS, tDH, tWC, tADL, tCH, tWW, tCS, tRP, tRC, tREA, tRR, tOH, tWHR, tAR, tWB, tREH, tRHW, tWHR2, tBERS, tR, tPROG</p> <p>Sync Programmable Timing: tADL, tCAD, tCALS, tDS, tCCS, tDQSS, tWB, tWW, tDQSCK, tRHW, tWHR, tWPRE, tWPST, tBERS, tPROG, tR</p> <p>Toggle Programmable Timing: tADL, tCALS, tCALH, tCS, tCH, tAR, tRR, tWB, tWHR, tWC, tWP, tWW, tWHR2, tWPRE, tCAS, tCAH, tCC, tDTCC, tRP, tCDQSS, tCDQSH, tWPST, tWPSTH, tRPRE, tDQSRE, tRPST, tRPSTH, tBERS, tR, tPROG, tDS, tDH</p>
	1 pair of clock per IC socket

DC Specification (Hardware)

	NandFlash
Variable Power Supplies	Vdd: 1.2V to 4.0V, resolution 0.01V, 4A, +/- 2%, per DUT site
Icc Measurement (Based on measurement of each site)	Operating Icc Measurement: R1: 0 - 3A (+/- 50mA) R2: 3 - 10A (+/- 100 mA) Stand-by Icc Measurement: R1: 0uA - 10uA, +/- 1uA R2: 10uA - 100uA, +/- 2uA R3: 100uA - 1mA, +/- 25uA R4: 1mA - 40mA, +/- 450uA
Leakage Current Measurement	R1: 0uA - 10uA, +/- 1uA R2: 10uA - 100uA, +/- 2uA R3: 100uA - 1mA, +/- 25uA R4: 1mA - 40mA, +/- 450uA (Based on measurement of each site)
DC Tests	DC Shorts/Leakage, Icc

System and Software Features

	NandFlash
System and Software Features	Support AC/ DC/ Icc parametric tests
	Built in Icc patterns include sequential read operating current, program operating current, erase operating current and stand-by current (TTL)
	Support Shorts/Leakage test
	Supports both large block and small block architecture
	Supports Block/ Page/ Column modes
	Supports cache read, sequential read and copy back Flexible bad block management available for read bad block
System and Software Features	Over 35 industry standard AC test patterns available Over 20, 15, 30 AC timing parameters for AC parametric testing (Async, Sync and Toggle respectively)
	Support both text and graphical result display
	Support Single IC and MCP device form factors
	For TCII-1600 ICMCP, support 16 DUT Sites in x8, 8 DUT Sites in x16, 4 DUT Sites in x32 parallel tests For TCIII-1600 ICMCP, support 64 DUT Sites in x8, 32 DUT Sites in x16, 16 DUT Sites in x32 parallel tests
	Heat Chamber and Handler Interface optional
Min. Control PC	Windows XP+ and networking interface
Test Unit Dimensions (W x D x H)	For TCII-1600 ICMCP: 18" (450mm) x 12" (295mm) x 10" (245mm) For TCIII-1600 ICMCP: 40" (1000mm) x 24" (600mm) x 14" (360mm)
AC Power Supply	110 – 240 VAC, 50/60 Hz